#### CE EMC

#### **TEST REPORT**

#### For

#### **Intel Pentium4 APCI Half-Size SBC**

Model: HSB-835A

**Trade Name: AAEON** 

Issued to

AAEON Technology Inc. 5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City, Taipei, Taiwan, R.O.C.

Issued by



Compliance Certification Services Inc. Hsintien Lab.

No. 165, Chunghsen Road, Hsintien City Taipei Hsien, Taiwan TEL: (02) 2217-0894

FAX: (02) 2217-1029



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#### 1 TEST RESULT CERTIFICATION

Applicant: AAEON Technology Inc.

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City,

Date of Issue: January 17, 2005

Taipei, Taiwan, R.O.C.

Manufacturer: AAEON Technology Inc.

5F, No.135, Lane 235, Pao Chiao Rd., Hsin-Tien City,

Taipei, Taiwan, R.O.C.

**Equipment Under Test:** Intel Pentium4 APCI Half-Size SBC

Trade Name: AAEON

Model: HSB-835A

**Detailed EUT Description:** See Item 2 of this report

**Date of Test:** January 4, 2005 ~ January 6, 2005

Applicable Standard	Class/Limit/Criterion	Test Result		
EN 55022: 1998 + A1: 2000 + A2: 2003	Class A	No non-compliance noted		
EN 61000-3-2: 2000	Class D	No non-compliance noted		
EN 61000-3-3: 1995 + A1: 2001	Limit	No non-compliance noted		
EN 55024:1998 + A1: 2001 + A2: 2003, including	ng			
IEC 61000-4-2: 1995 +A1: 1998 +A2: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-3: 1995 +A1: 1998 +A2: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-4: 1995 +A1: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-5: 1995 +A1: 2000	Criterion B	No non-compliance noted		
IEC 61000-4-6: 1996 +A1: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-8: 1993 +A1: 2000	Criterion A	No non-compliance noted		
IEC 61000-4-11: 1994 +A1: 2000	Criterion B/C/C	No non-compliance noted		
Deviation from Applicable Standard				
None				

The above equipment was tested by Compliance Certification Services Inc. for compliance with the requirements set forth in the EMC Directive 89/336/EMC and the technical standards mentioned above. The results of testing in this report apply only to the product/system, which was tested. Other similar equipment will not necessarily produce the same results due to production tolerance and measurement uncertainties.

Approved by:

David Wang

Manager of Hsintien Laboratory

Compliance Certification Services Inc.

Reviewed by:

Vince Chiang

Section Manager of Hsintjen Laboratory

Compliance Certification Services Inc.

# 2 EUT DESCRIPTION

Product	Intel Pentium4 APCI Half-Size SBC		
Trade Name	AAEON		
Model	HSB-835A		
Housing Type	Metal case		
Power Adaptor Power Rating	110VAC~230VAC		
AC Power During Test	230VAC / 50 Hz to AC Adaptor		
Power Supply Manufacturer	Seventeam		
Power Supply Model Number	ST-300HLP		
AC Power Cord Type	Unshielded, 1.8m (Detachable)		
OSC/Clock Frequencies	32.768kHz; 12MHz; 14.318MHz; 25MHz; 33MHz; 48MHz; 66MHz; 100MHz; 133MHz		

#### I/O PORT OF EUT

I/O PORT TYPE	Q'TY	TESTED WITH
1). PIO Port	1	1
2). SIO Port	2	2
3). PS/2 one to two adaptor	1	1
4). VIDEO-OUT Port (VGA)	1	1
5). AUDIO OUT Port	1	1
6). Microphone Port	1	1
7). Earphone Port	1	1
8). LAN Port	1	1
9). USB 2.0 Port	7	7

Note: Client consigns only one model sample (Model Number is HSB-835A) to test.

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# 3 TEST METHODOLOGY

## 3.1 EUT SYSTEM OPERATION

- 1. Windows XP boots system.
- 2. Run Emctest.exe to activate all peripherals and display "H" pattern on monitor screen.

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- 3. Run 'F.bat, G.bat, H.bat, I.bat, J.bat, K.bat, L.bat" to test USB 2.0 HDD.
- 4. Run Windows media player to play music.
- 5. Press the start menu, select executive and type ping 192.168.0.13 –t(EUT), ping 192.168.0.23 –t(Server Notebook).

Note: Test program is self-repeating throughout the test.

#### 3.2 DECISION OF FINAL TEST MODE

1. The following test mode(s) were scanned during the preliminary test:

#### Mode:

#### 1. Normal Mode

2. After the preliminary scan, the following test mode(s) was found to produce the highest emission level.

**Conduction:** Mode 1 **Radiation:** Mode 1

Then, the EUT configuration and cable configuration of the above highest emission mode was chosen for all final test items.

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# 4 SETUP OF EQUIPMENT UNDER TEST

#### **Setup Diagram**

See test photographs attached in Appendix I for the actual connections between EUT and support equipment.

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#### **Support Equipment**

#### **EUT Devices:**

No	Equipment	Model #	Serial #	FCC/BSMI ID	Trade Name
1	HDD	Fireball 3 ATA/133	N/A	BSMI: D33029	Maxtor
2	POWER	ST-300HLP	N/A	BSMI ID: 3912 A045 DOC	Seventeam
3	CD/R	CD-2052E	N/A	BSMI ID: 3902A934 DOC	AFREEY
4	FLOPPY DISK	FD-235HF	3010687	BSMI ID: 3902A889	TEAC
5	CPU (3.2GHz)	Pentium4	N/A	N/A	INTEL
6	RAM (1GB)	1G DDR400 DIMM3-3-3	N/A	N/A	SAMSUNG
7	Mother Board	HSB-835A	N/A	N/A	AAEON
8	CPU Card	HSB-835A	N/A	N/A	AAEON
9	Audio + USB Board	PER-YC02	N/A	N/A	AAEON
10	Back Plan Board	BP-214SA-P616 Rev. A1.1	N/A	N/A	AAEON

#### **Peripherals Devices:**

No	Equipment	Model	Serial No.	FCC/ BSMI ID	Trade Name	Data Cable	Power Cord
1	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 1.8m	N/A
2	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 1.8m	N/A
3	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 1.8m	N/A
4	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 1.8m	N/A
5	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 1.8m	N/A
6	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912A002	TeraSys	Shielded, 1.8m	N/A
7	USB 2.0 HDD	F12-U	N/A	BSMI ID: 4912 A002	TeraSys	Shielded, 1.8m	N/A
8	Player	MIC-31	N/A	N/A	HEAD PHONE	Unshielded, 1.8m	N/A
9	Ear. / Mic.	RQ-L11LT	N/A	BSMI ID: 3913A162	Panasonic	Unshielded, 1.8m	N/A
10	PS/2 Mouse	M071KC	443029438	DOC BSMI: R41108	DELL	Shielded, 1.8m	N/A
11	PS/2 Keyboard	SK-8110	N/A	DOC BSMI: T3A002	DELL	Shielded, 1.8m	N/A
12	Printer	C61	N/A	BSMI ID: 3912E328	EPSON	Shielded, 1.8m	Unshielded, 1.8m
13	Modem	5JEG4033MKO	N/A	5RJTAI-35500-M5-E	TOP - SOLUTION	Shielded, 1.8m	Unshielded, 1.8m
14	Modem	5JEG4033MKO	N/A	5RJTAI-35500-M5-E	TOP - SOLUTION	Shielded, 1.8m	Unshielded, 1.8m
15	Monitor	710V	GS17H9NXA05858E	DOC BSMI: R33475	SAMSUNG	Shielded, 1.8m with two cores	Unshielded, 1.8m
16	Server Notebook	2659-FT1	AK- VHXOH 02/10 C	ANOPSIWLIV	IBM	Unshielded, 10m	Unshielded, 1.8m with a core

Note: All the above equipment/cables were placed in worse case positions to maximize emission signals during emission test. Grounding: Grounding was in accordance with the manufacturer's requirements and conditions for the intended use.

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#### 5 FACILITIES AND ACCREDITATIONS

#### **5.1 FACILITIES**

All measurement facilities used to collect the measurement data are located at CCS Taiwan Hsintien Lab at No. 165, Chunghsen Road, Hsintien City, Taipei Hsien, Taiwan.

The measurement facilities are constructed in conformance with the requirements of CISPR 16-1, ANSI C63.4 and other equivalent standards.

#### 5.2 LABORATORY ACCREDITATIONS AND LISTINGS

The test facilities used to perform Electromagnetic compatibility tests are registered or accredited by the organizations listed in the following table which includes the recognized scope specifically.

Country	Agency	Scope of Accreditation	Logo
USA	CFR 47, FCC Part 15/18 using ANSI 63.4; AS/NZS 3548; VCCI V3; CNS 13438; CNS 13439; CNS 13783; CNS 14115 CISPR 11/EN 55011; CISPR 14-1/EN 55014-1; CISPR 15/EN 55015; CISPR 22/EN 55022; EN 50081-1/EN 61000-6-3; EN 50082-1/EN 61000-6-4; IEC/EN 61000-4-2, IEC/EN 61000-4-3, IEC/EN 61000-4-4, IEC/EN 61000-4-5, IEC/EN 61000-4-6, IEC/EN 61000-3-3; CISPR 24/EN 55024 CISPR 14-2/EN 55014-2; EN 50081-2/EN 61000-6-1; EN 50082-2/EN 61000-6-2.		ACCREDITED
USA	FCC	3/10 meter Open Area Test Sites to perform FCC Part 15/18 measurements	<b>F</b> © 250366
Japan	VCCI	3/10 meter Open Area Test Sites and Line Conducted Test Room to perform conducted/radiated measurements	VCCI R-1434/1630~4 C-1511/1882
Norway	NEMKO	EN 50081-1/2, EN 50082-1/2, IEC 61000-6-1/2/3/4, EN 50091-2, EN 50130-4, EN 55011, EN 55013, EN 55014-1/2, EN 55015, EN 55022, EN 55024, EN 61000-3-2/3, EN 61326-1, IEC 61000-4-2/3/4/5/6/8/11, Cispr 16-1/2/3/4	ELA 103
Taiwan	CNLA	47 CFR FCC Part 15 Subpart B, EN 61000-3-2, EN 61000-3-3, CNS 13439, CNS 13783-1, CNS 13438, AS/NZS 3548, VCCI, CNS 13022-1/2/3, EN 55022, EN 55013, EN 55014-1, EN 61000-4-2/3/4/5/6/8/11, ENV 50204, ENV 50141, ENV 50142	1108 ILAC MRA
Taiwan	BSMI	CNS 13438, CNS 13783-1, CNS 13439	SL2-IN-E-0005 SL2-A1-E-0005 SL2-R1-E-0005 SL2-R2-E-0005

**Note:** No part of this report may be used to claim or imply product endorsement by CNLA, A2LA or other government agency.

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# INSTRUMENT AND CALIBRATION

#### 6.1 MEASURING INSTRUMENT CALIBRATION

The measuring equipment utilized to perform the tests documented in this report has been calibrated once a year or in accordance with the manufacturer's recommendations, and is traceable to recognized national standards.

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## **6.2 TEST AND MEASUREMENT EQUIPMENT**

The following list contains measurement equipment used for testing. The equipment conforms to the requirement of CISPR 16-1, ANSI C63.2 and. other required standards.

Calibration of all test and measurement, including any accessories that may effect such calibration, is checked frequently to ensure the accuracy. Adjustments are made and correction factors are applied in accordance with the instructions contained in the respective manual.

#### **Equipment Used for Emission Measurement**

	Open Area Test Site # I						
EQUIPMENT	MFR	MODEL	SERIAL NUMBER	CAL. DUE			
SITE NSA	CCS	I Site	N/A	09/17/2005			
MEASURE RECEIVER	SCHAFFNER	SCR3501	338	07/05/2005			
SPECTRUM ANALYZER	ADVANTEST	R3132	120900008	No Calibration Required			
ANTENNA	SCHAFFNER	CBL 6112B	2809	09/24/2005			
AMPLIFIER	SCHAFFNER	CPA9231A	3626	10/08/2005			
CABLE	BELDEN	9913	N-TYPE #I1	10/08/2005			
ATTENUATOR	MCL	UNAT-6	AT06-3	10/08/2005			
THERMO- HYGRO METER	TFA	N/A	NO.2	11/09/2005			
DECOUPLING NETWORK	FCC	F-201-DCN-5-6MM	22、24	09/07/2005			

Note: The measurement uncertainty is less than +/- 3.36dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

Conducted Emission Test Site # B						
EQUIPMENT	MFR	MODEL	SERIAL NUMBER	CAL. DUE		
TEST RECEIVER	R&S	ESHS20	840455/006	03/07/2005		
LISN (EUT)	SCHWARZBECK	NSLK 8127	8127382	01/05/2005		
LISN	SOLAR	8012-50-R-24-BNC	8305114	02/10/2005		
BNC CABLE	MIYAZAKI	5D-FB	BNC A1	01/30/2005		
THERMO- HYGRO METER	TOP	HA-202	9303-1	03/24/2005		
4-Wire ISN	R&S	ENY41	100006	07/01/2005		
2-Wire ISN	R&S	ENY22	100020	07/01/2005		

Note: The measurement uncertainty is less than +/- 2.83dB, which is evaluated as per the NAMAS NIS 81 and CISPR/A/291/CDV.

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Power Harmonic & Voltage Fluctuation/Flicker Test Site (EN 61000-3-2&-3-3)						
Manufacturer/Type Model No. Serial No. Cal. Due						
Schaffner / Signal Conditioning Unit	CCN 1000-1	72122	12/05/2005			
Schaffner / 5KVA AC Power Source	NSG 1007	55131	No Calibration Required			

## **Equipment Used for Immunity Measurement**

ESD Test Site (EN 61000-4-2)						
Manufacturer/Type Model No. Serial No. Cal. Due						
Schaffner / ESD Simulator	NSG 438	129	04/21/2005			
Stockburger / Aneroid Barometer	Barometer	9303	03/30/2005			
TOP / Thermo-Hygro meter	HA-202	9303-1	03/24/2005			

Radiated Electromagnetic Field Immunity Test Site (EN 61000-4-3)					
Manufacturer/Type	Model No.	Serial No.	Cal. Due		
Calibration of Field	Chamber#RS	RS3H-6 / RS3V-6	07/02/2005		
Agilent / Signal Generator	E4421B	MY43350597	05/30/2005		
AR / Electric Field Probe	FP6001	305657	03/17/2005		
Boonton / RF Voltmeter	9200B	328001AE	02/18/2005		
BNC / Function Generator	625	25451	02/18/2005		
AR / Amplifier	100W1000M1	17564	No Calibration Required		
Werlatone Inc. / Direction Coupler	C2630	4121	No Calibration Required		
Frankonia / Broadband Antenna	BTA-M	030001M	No Calibration Required		
TOP / Thermo-Hygro meter	HA-202	9303-2	03/24/2005		

Fast Transients/Burst Test Site (EN 61000-4-4)					
Manufacturer/Type	Model No.	Serial No.	Cal. Due		
Schaffner / EFT Generator	BEST EMC V2.3	200031A024SC	11/09/2005		
Schaffner / Capacitive Clamp	N/A	N/A	No Calibration Required		

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Su	lite (EN 61000-4-5)			
Manufacturer/Type	Model No.	Serial No.	Cal. Due	
Schaffner / Surger Generator	BEST EMC V2.3	200031A024SC	11/09/2005	
Schaffner / Signal and Data Lines Coupling Network	CDN118	19328	No Calibration Required	

CS test (EN 61000-4-6)							
Manufacturer/Type	Model No.	Serial No.	Cal. Due				
Schaffner / RF Generator	NSG 2070-1	1061	08/02/2005				
Schaffner / CDN	CDN M316	19600	08/02/2005				
Schaffner / CDN	CDN M216	19294	08/02/2005				
Schaffner / EM Clamp	KEMZ 801	19227	03/02/2005				
Schaffner / CDN	CDN A800	17885	08/02/2005				
Schaffner / CDN	CDN T002	15881	01/30/2005				
FCC / CDN	FCC-801-T8-RJ45	04025	06/24/2005				
Schaffner / Attenuator	INA2070-1	2061	No Calibration Required				
FCC / CDN	FCC-801-T4-RJ45	04031	08/19/2005				

Power Frequency Magnetic Field Immunity test (EN 61000-4-8)							
Manufacturer/Type	Model No. Serial No.		Cal. Due				
Schaffner / Induction Coil Interface	INA 21141	6009	No Calibration Required				
Schaffner / 5KVA AC Power Source	NSG 1007	55131	No Calibration Required				
CHY/ TRMS Clamp Meter	932C	2K0900285	10/12/2005				
Sypris / Magnetic Field Meter	4080	0247	02/11/2005				

Voltage Dips/Short Interruption and Voltage Variation Immunity test (EN 61000-4-						
Manufacturer/Type	Model No.	l No. Serial No. Cal. I				
Schaffner / Dips/Interruption/Variations Tester	BEST EMC V2.3	200031A024SC	11/09/2005			
Protronix / Digital Power Meter	1201	201091	08/31/2005			

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# 7 LINE CONDUCTED & RADIATED EMISSION TEST

#### **7.1 LIMIT**

#### **Maximum permissible level of Line Conducted Emission**

FREQUENCY	Class A	(dBuV)	Class B (dBuV)		
(MHz)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	79	66	66 - 56	56 - 46	
0.50 - 5.0	73	60	56	46	
5.0 - 30.0	73	60	60	50	

*Note:* The lower limit shall apply at the transition frequency.

# <u>Maximum permissible level of Common Mode Conducted Emission</u> (<u>Telecommunication Ports</u>)

#### **CLASS A**

FREQUENCY	Voltage Limit (dBuV)		Current Limit (dBuA)		
(MHz)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	97 – 87	84 - 74	53 – 43	40 – 30	
0.5 - 30.0	87	74	43	30	

#### **CLASS B**

FREQUENCY	Voltage Limit (dBuV)		Current Limit (dBuA)		
(MHz)	Quasi-peak	Average	Quasi-peak	Average	
0.15 - 0.5	84 - 74	74 - 64	40 – 30	30 - 20	
0.5 - 30.0	74	64	30	20	

*Note:* The lower limit shall apply at the transition frequency.

#### Maximum permissible level of Radiated Emission measured at 10 meter

FREQUENCY	Class A (dBuV/m)	Class B (dBuV/m)		
(MHz)	Quasi-peak	Quasi-peak		
30 – 230	40	30		
230 - 1000	47	37		

*Note:* The lower limit shall apply at the transition frequency.

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#### 7.2 TEST PROCEDURE OF LINE CONDUCTED EMISSION

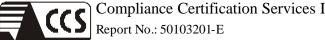
#### **Procedure of Preliminary Test**

- The EUT was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden table with a height of 0.8 meters is used and is placed on the ground plane as per EN 55022 (see Test Facility for the dimensions of the ground plane used). When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
- Support equipment, if needed, was placed as per EN 55022.
- All I/O cables were positioned to simulate typical actual usage as per EN 55022.
- The test system with EUT received AC power, 230V/50Hz, through a Line Impedance Stabilization Network (LISN), which supplied power source and was grounded to the ground plane.
- All support equipment received power from a second LISN.
- The EUT test program was started. Emissions were measured on each current carrying line of the EUT using an EMI Test Receiver connected to the LISN powering the EUT.
- The Receiver scanned from 150kHz to 30MHz for emissions in each of the test modes.
- During the above scans, the emissions were maximized by cable manipulation.
- The test mode(s) described in Item 3.2 were scanned during the preliminary test.
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT configuration and cable configuration of the above highest emission level were recorded for reference of the final test.

#### **Procedure of Final Test**

- EUT and support equipment were set up on the test bench as per the configuration with highest emission level in the preliminary test.
- A scan was taken on both power lines, Line 1 and Line 2, recording at least the six highest emissions. Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit. If EUT emission level was less –2dB to the Average limit in Q.P. mode, then the emission signal was re-checked using an Average detector.
- The test data of the worst-case condition(s) was recorded.

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#### **Data Sample:**

Freq. MHz	Read Level dBuV	Factor dB	Level dBuV	Limit dBuV	Over Limit dB	Reading Type (P/Q/A)	Line (L1/L2)
x.xx	42.95	0.55	43.50	73	-29.50	Q	L1

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= Emission frequency in MHz Freq.

Read Level = Uncorrected Analyzer/Receiver reading Factor = Insertion loss of LISN + Cable Loss

Level = Read Level + Factor Limit = Limit stated in standard Over Limit = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading = Average Reading Α

L1 = Hot side 1.2 = Neutral side

#### **Calculation Formula**

Over Limit (dB) = Level (dBuV) – Limit (dBuV)

# 7.3 TEST PROCEDURE OF COMMON MODE CONDUCTED EMISSION FOR TELECOMMUNICATION PORT

- Selecting ISN for unscreened cable or a current probe for screened cable to take measurement.
- The port of the EUT was connected to the remote side support equipment through the ISN/Current Probe and communication in normal condition.
- Making a overall range scan by using the test receiver controlled by controller and record at least six highest emissions for showing in the test report.
- Emission frequency and amplitude were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit.
- In case of measuring on the screened cable, the current limit shall be applied, otherwise the voltage limit should be applied.
- The following test mode(s) were scanned during the preliminary test:

#### **Mode(s):**

- 1 **100 Mbps**
- 2 10 Mbps
- After the preliminary scan, we found the following test mode(s) producing the highest emission level and test data of the worst case was recorded.

Mode: 1.

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#### **Data Sample:**

Freq. MHz	Read Level dBuV	Factor dB	Level dBuV	Limit dBuV	Over Limit dB	Reading Type (P/Q/A)
x.xx	62.95	0.55	63.50	87	-23.50	Q

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Freq. = Emission frequency in MHz

Read Level = Uncorrected Analyzer/Receiver reading Factor = Insertion loss of ISN + Cable Loss

Level = Read Level + Factor
Limit = Limit stated in standard
Over Limit = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

#### **Calculation Formula**

Over Limit (dB) = Level (dBuV) – Limit (dBuV)

#### 7.4 TEST PROCEDURE OF RADIATED EMISSION

#### **Procedure of Preliminary Test**

- The equipment was set up as per the test configuration to simulate typical usage per the user's manual. When the EUT is a tabletop system, a wooden turntable with a height of 0.8 meters is used which is placed on the ground plane. When the EUT is a floor-standing equipment, it is placed on the ground plane which has a 3-12 mm non-conductive covering to insulate the EUT from the ground plane.
  - Support equipment, if needed, was placed as per EN 55022.
  - All I/O cables were positioned to simulate typical usage as per EN 55022.
  - The EUT received AC power source, 230V/50Hz, from the outlet socket under the turntable. All support equipment received power from another socket under the turntable.
  - Mains cables, telephone lines or other connections to auxiliary equipment located outside the
    test are shall drape to the floor, be fitted with ferrite clamps or ferrite tubes placed on the floor
    at the point where the cable reaches the floor and then routed to the place where they leave the
    turntable. No. extension cords shall be used to mains receptacle.
  - The antenna was placed at 10 meter away from the EUT as stated in EN 55022. The antenna connected to the Spectrum Analyzer via a cable and at times a pre-amplifier would be used.
  - The Analyzer / Receiver quickly scanned from 30MHz to 1000MHz. The EUT test program was started. Emissions were scanned and measured rotating the EUT to 360 degrees and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.

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- The test mode(s) described in Item 3.2 were scanned during the preliminary test:
- After the preliminary scan, we found the test mode described in Item 3.2 producing the highest emission level.
- The EUT and cable configuration, antenna position, polarization and turntable position of the above highest emission level were recorded for the final test.

#### **Procedure of Final Test**

- EUT and support equipment were set up on the turntable as per the configuration with highest emission level in the preliminary test.
- The Analyzer / Receiver scanned from 30MHz to 1000MHz. Emissions were scanned and measured rotating the EUT to 360 degrees, varying cable placement and positioning the antenna 1 to 4 meters above the ground plane, in both the vertical and the horizontal polarization, to maximize the emission reading level.
- Recorded at least the six highest emissions. Emission frequency, amplitude, antenna position, polarization and turntable position were recorded into a computer in which correction factors were used to calculate the emission level and compare reading to the applicable limit and only Q.P. reading is presented.

#### **Data Sample:**

Freq. MHz	Amptd dBuV/m	Margin dB	Limit dBuV/m	Reading dBuV	Factor dB/m	Reading Type (P/Q/A)	Pol. (H/V)
x.xx	26.2	-13.8	40	14	12.2	Q	Н

Freq. = Emission frequency in MHz

Reading = Uncorrected Analyzer/Receiver reading

Factor = Antenna Factor + Cable Loss + Attenuator (3/6/10dB) – Amplifier Gain

Amptd = Uncorrected Analyzer/Receiver reading + Factor

Limit = Limit stated in standard

Margin = Reading in reference to limit

P = Peak Reading

Q = Quasi-peak Reading A = Average Reading

H = Antenna Polarization: Horizontal V = Antenna Polarization: Vertical

#### **Calculation Formula**

Margin (dB) = Amptd (dBuV/m) – Limit (dBuV/m)

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# 7.5 TEST RESULTS

#### **Line Conducted Emission**

Model: HSB-835A Test Mode: Mode 1

**Temperature:** 20 °C **Humidity:** 80% RH

**Test Results:** Passed **Tested by:** Webber Jung

(The chart below shows the highest readings taken from the final data, see **Appendix III** for details.)

	Six Highest Conducted Emission Readings						
Fre	quency Ran	ge Investiga	ated	150 kHz to 30 MHz			
Freq (MHz)	Read Level (dBuV)	Factor (dB)	Level (dBuV)	Limit Line (dBuV)	Over Limit (dB)	Reading Type (P/Q/A)	Line (L1/L2)
3.964	35.06	10.08	45.14	73.00	-27.86	P	L1
6.914	27.76	10.12	37.88	73.00	-35.12	P	L1
11.080	30.36	10.19	40.55	73.00	-32.45	P	L1
3.964	35.04	10.08	45.12	73.00	-27.88	P	L2
6.914	27.76	10.12	37.88	73.00	-35.12	P	L2
11.080	28.68	10.19	38.87	73.00	-34.13	P	L2

NOTE: The emission level was or more than 2dB below the Average limit, so no re-check anymore.

#### **Common Mode Conducted Emission**

	Six Highest Conducted Emission Readings					
Frequency F	Frequency Range Investigated 150 kHz to 30 MHz					
Freq (MHz)	Read Level (dBuV)	Factor (dB)	Level (dBuV)	Limit Line (dBuV)	Over Limit (dB)	Reading Type (P/Q/A)
0.479	60.08	20.28	80.36	87.36	-7.00	P
0.479	52.39	20.28	72.67	74.36	-1.69	A
0.724	55.68	20.23	75.91	87.00	-11.09	P
0.899	52.56	20.20	72.76	87.00	-14.24	P
1.317	42.46	20.16	62.62	87.00	-24.38	P
2.167	44.70	20.12	64.82	87.00	-22.18	P
3.985	43.96	20.18	64.14	87.00	-22.86	P
15.552	44.98	20.20	65.18	87.00	-21.82	P

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## **Radiated Emission**

Model: HSB-835A Test Mode: Mode 1

**Temperature:** 18°C **Humidity:** 85% RH

Test Results: Pass Tested by: Webber Jung

(The chart below shows the highest readings taken from the final data, see Appendix III for details.)

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	Six Highest Radiated Emission Readings						
Frequency	Range Inve	estigated		30 N	MHz to 1000	MHz at 10	m
Freq (MHz)	Amptd (dBuV/m)	Margin (dB)	Limit (dBuV/m)	Reading (dBuV)	Factor (dB/m)	Reading Type (P/Q/A)	Pol. (H/V)
133.1100	34.94	-5.06	40.00	44.89	-9.95	P	V
133.2300	36.53	-3.47	40.00	46.48	-9.95	P	H
240.0550	41.66	-5.34	47.00	50.30	-8.64	Q	H
400.0470	42.16	-4.84	47.00	45.81	-3.65	P	H
465.7020	41.87	-5.13	47.00	43.73	-1.86	P	H
749.6950	41.78	-5.22	47.00	40.47	1.31	P	H

NOTE: None.

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# 8 POWER HARMONICS TEST

**Port** : AC mains

**Basic Standard** : EN 61000-3-2 (2000)

Limits :  $\square$  CLASS A;  $\overline{V}$  CLASS D

**Teste d by** : Marion Yu

**Temperature** : 17°C **Humidity** : 51%

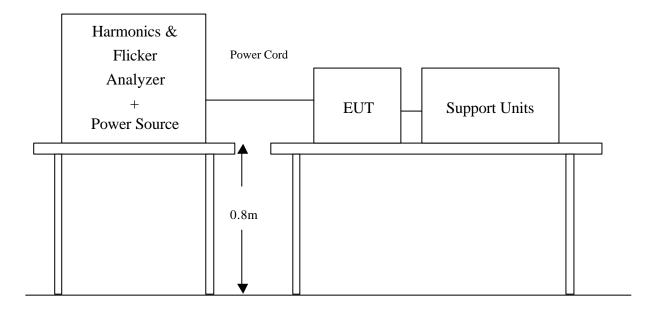
# **Limit:**

Limits for Class A equipment				
Harmonics	Max. permissible			
Order	harmonics current			
n	A			
Od	d harmonics			
3	2.30			
5	1.14			
7	0.77			
9	0.40			
11	0.33			
13	0.21			
15<=n<=39	0.15x15/n			
Eve	en harmonics			
2	1.08			
4	0.43			
6	0.30			
8<=n<=40	0.23x8/n			

	Limits for Class D equip	oment
Harmonics Order n	Max. permissible harmonics current per watt mA/W	Max. permissible harmonics current
	Odd Harmonics only	7
3	3.4	2.30
5	1.9	1.14
7	1.0	0.77
9	0.5	0.40
11	0.35	0.33
13	0.30	0.21
15<=n<=39	3.85/n	0.15x15/n

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# **Block Diagram of Test Setup:**



#### **Test Procedure:**

- a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- b. The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the time necessary for the EUT to be exercised.

<u>Test Result</u>: (See Appendix II for details)

	☐ FAIL
<b>Note:</b> No function degraded during the tests.	

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# 9 POWER VOLTAGE FLUCTUATION / FLICKER TEST

**Port** : AC mains

**Basic Standard** : EN 61000-3-3 (1995 + A1: 2001)

**Limits** : § of EN 61000-3-3

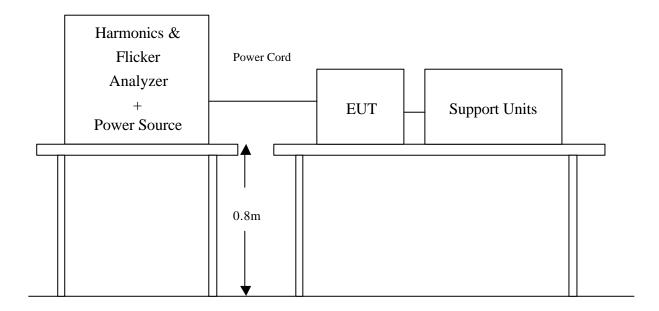
**Teste d by** : Marion Yu

**Temperature** : 17°C **Humidity** : 51%

# **Limit:**

TEST ITEM	LIMIT	REMARK	
$P_{st}$	1.0 P <sub>st</sub> means short-term flicker indicator.		
$P_{lt}$	0.65	P <sub>lt</sub> means long-term flicker indicator.	
T <sub>dt</sub> (ms)	500	$T_{dt}$ means maximum time that dt exceeds 3.3 %.	
d <sub>max</sub> (%)	4%	d <sub>max</sub> means maximum relative voltage change.	
dc (%)	3.3%	dc means relative steady-state voltage change	

# **Block Diagram of Test Setup:**



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# **Test Procedure:**

- a. The EUT was placed on the top of a wooden table 0.8 meters above the ground and operated to produce the most unfavorable sequence of voltage changes under normal operating conditions.
- b. During the flick measurement, the measure time shall include that part of whole operation cycle in which the EUT produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

**Test Result:** (See Appendix II for details)

TEST PARAMETER	MEASUREMENT VALUE	LIMIT	RESULT
P <sub>st</sub>	0.001	1.0	Pass
$P_{lt}$	0.001	0.65	Pass
T <sub>dt</sub> (ms)	0.0	500	Pass
d <sub>max</sub> (%)	0.00	4%	Pass
dc (%)	0.00	3.3%	Pass

Note: None.

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# 10 ELECTROSTATIC DISCHARGE (ESD) IMMUNITY TEST

**Port** : Enclosure

**Basic Standard**: IEC/EN 61000-4-2

**Test Level** :  $\pm 8 \text{ kV (Air Discharge)}$ 

±4 kV (Contact Discharge) ±4 kV (Indirect Discharge)

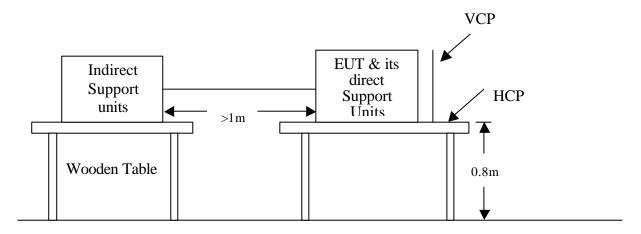
**Performance Criterion:** B (Standard Required)

Teste d by : Marion Yu
Temperature : 17°C
Humidity : 51%

Pressure : 1009mbar

# **Block Diagram of Test Setup:**

(The 470 k ohm resistors are installed per standard requirement.)



Ground Reference Plane

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#### **Test Procedure:**

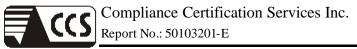
- 1. The EUT was located 0.1 m minimum from all sides of the HCP.
- 2. The indirect support units were located 1 m minimum away from the EUT, but direct support unit was/were located at same location as EUT on the HCP and keep at a distance of 10 cm with EUT.
- 3. As per the requirement of EN 55024; applying direct contact discharge at the sides other than front of EUT at minimum 50 discharges (25 positive and 25 negative) if applicable, can't be applied direct contact discharge side of EUT then the indirect discharge shall be applied. One of the test points shall be subjected to at least 50 indirect discharge (contact) to the front edge of horizontal coupling plane.
- 4. Other parts of EUT where it is not possible to perform contact discharge then selecting appropriate points of EUT for air discharge, a minimum of 10 single air discharges shall be applied.
- 5. The application of ESD to the contact of open connectors is not required.
- 6. The EUT direct connection units also need to be applied ESD at the port of EUT cable connected.
- 7. Putting a mark on EUT to show tested points. The following test condition was followed during the tests.

*Note:* As per IEC/EN 61000-4-2, two 470k bleed resistors cable is connected between the EUT and HCP during the test applicable for power ungrounded or battery operating unit only.

The electrostatic discharges were applied as follows:

Amount of discharge	Voltage	Coupling	Result (Pass/Fail)
Mini 10 /Point	$\pm 8 \text{ kV}$	Air Discharge	Pass
Mini 25 /Point	±4 kV	Contact Discharge	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge HCP (Front)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Right)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Left)	Pass
Mini 25 /Point	± 4 kV	Indirect Discharge VCP (Back)	Pass

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# Performance & Result:

$\boxtimes$	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.				
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.				
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.				
Ol	Observation: No function degraded during the tests.					

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# 11 RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

**Port** : Enclosure

**Basic Standard**: IEC/EN 61000-4-3

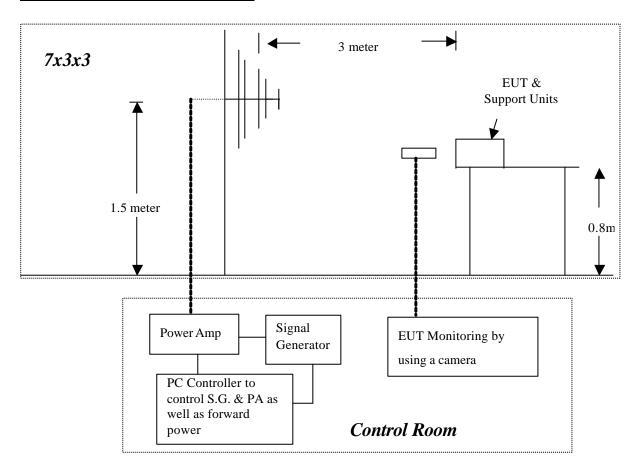
**Requirements** : 3 V/m / with 80% AM. 1kHz Modulation.

**Performance Criterion:** A (Standard Required)

Tested by : Marion Yu
Temperature : 17°C
Humidity : 51%

Pressure : 1009mbar

# **Block Diagram of Test Setup:**



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**Test Procedure:** 

1. The EUT and support units were located at the edge of supporting table keep 3 meter away from transmitting antenna, it just the calibrated square area of field uniformity.

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- 2. Adjusting the cables to be exposed to the electromagnetic filed as possible.
- 3. Performing a Radiated Emission Scan in range of 30 to 1000 MHz prior to do RS test and records the more higher emission frequencies for the reference of RS test, due to antenna effectiveness.
- 4. Adjusting the monitoring camera to monitor the "H" message as clear as possible.
- 5. Setting the testing parameters of RS test software per IEC 61000-4-3.
- 6. Referring to the tested data of step 3 to performing the RS test from 80 to 1000 MHz.
- 7. Recording the test result in following table.
- 8. Changing the EUT to the other side and repeat step 3 to 6, until 4 sides of EUT were verified.

#### **IEC 61000-4-3 Final test conditions:**

Test level : 3V/m

Steps : 1 % of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Polarity	Position (°)	Result (Pass/Fail)
80-1000	3V/m	Yes	Н	Front	Pass
80-1000	3V/m	Yes	V	Front	Pass
80-1000	3V/m	Yes	Н	Right	Pass
80-1000	3V/m	Yes	V	Right	Pass
80-1000	3V/m	Yes	Н	Back	Pass
80-1000	3V/m	Yes	V	Back	Pass
80-1000	3V/m	Yes	Н	Left	Pass
80-1000	3V/m	Yes	V	Left	Pass

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# **Performance & Result:**

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.			
	Criterion B:	<b>B:</b> The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.			
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.			
Ol	<b>Observation:</b> No function degraded during the tests.				

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#### 12 FAST TRANSIENTS/BURST IMMUNITY TEST

**Port** : On Power Supply Lines and Data Line

**Basic Standard**: IEC/EN 61000-4-4

**Requirements** :  $\pm 1 \text{ kV}$  for Power Supply Line

± 0.5kV to Data Line

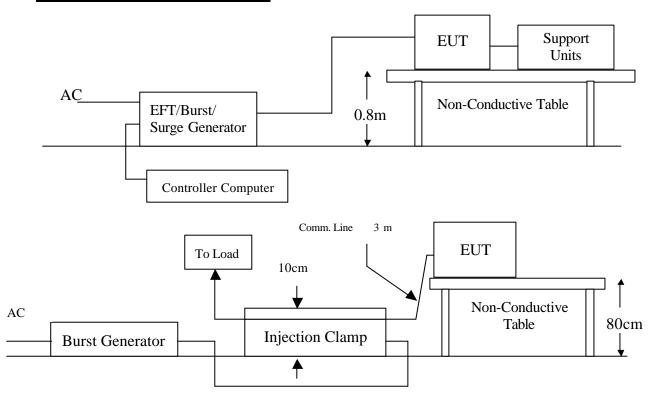
**Performance Criteria**: B (Standard Required)

**Teste d by** : Marion Yu

**Temperature** : 17°C **Humidity** : 51%

Pressure : 1009mbar

#### **Block Diagram of Test Setup:**



#### **Test Procedure:**

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground reference plane.
- 2. A 1.0 meter long power cord was attached to EUT during the test.
- 3. The length of communication cable between communication port and clamp was keeping within 1 meter.
- 4. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 5. Recorded the test result as shown in following table.

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## **Test conditions:**

Impulse Frequency: 5kHz
Tr/Th: 5/50ns
Burst Duration: 15ms
Burst Period: 3Hz

Inject Line	Voltage kV	Inject Method	Result (Pass/Fail)
L	± 1	Direct	Pass
N	± 1	Direct	Pass
PE	± 1	Direct	Pass
L+N	± 1	Direct	Pass
L + PE	± 1	Direct	Pass
N + PE	± 1	Direct	Pass
L + N + PE	± 1	Direct	Pass
RJ45	±0.5	Clamp	Pass

# **Performance & Result:**

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.			
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.			
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.			
Ol		AS $\pm 0.5$ kV EFT applying to RJ45, the data transmitting paused during test. could become normal after test stop.			

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# 13 SURGE IMMUNITY TEST

**Port** : Power Cord

Basic Standard : IEC/EN 61000-4-5

**Requirements** :  $\pm 1 \text{ kV (Line to Line)}$ 

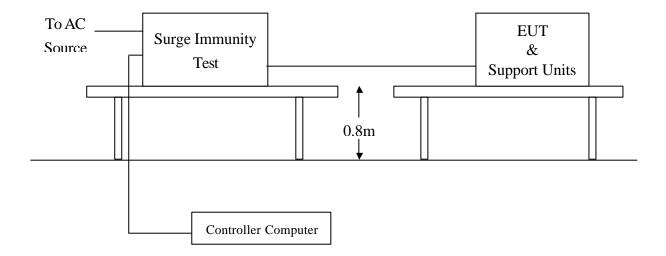
± 2 kV (Line to Ground)

**Performance Criteria**: B (Standard Required)

Tested by : Marion Yu
Temperature : 17°C
Humidity : 51%

**Pressure**: 1009mbar

#### **Block Diagram of Test Setup:**



# **Test Procedure:**

- 1. The EUT and support units were located on a wooden table 0.8 m away from ground floor.
- 2. Injected test voltage to the EUT ports from minimum to standard request or client request.
- 3. Recorded the test result as shown in following table.

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#### **Test conditions:**

Voltage Waveform : 1.2/50 us Current Waveform : 8/20 us

Polarity : Positive/Negative Phase angle : 0°, 90°, 270°

Number of Test : 5

Coupling Line	Voltage (kV)	Polarity	Coupling Method	Result (Pass/Fail)
L1-L2	1	Positive	Capacitive	Pass
L1-PE	2	Positive	Capacitive	Pass
L2-PE	2	Positive	Capacitive	Pass
L1-L2	1	Negative	Capacitive	Pass
L1-PE	2	Negative	Capacitive	Pass
L2-PE	2	Negative	Capacitive	Pass

# **Performance & Result:**

$\boxtimes$	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
	Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
		Where normal functioning of LAN can't be achieved because of the impact of JT, no test be required.

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# 14 CONDUCTED DISTRBANCE/INDUCED RADIO-FREQUENCY FIELD IMMUNITY TEST

**Port** : AC Port and Line Cable

**Basic Standard**: IEC/EN 61000-4-6

**Requirements** : 3 V, with 80% AM. 1kHz Modulation.

**Injection Method** : CDN-M3 for Power Cord

CDN-T4 for RJ45 Cable

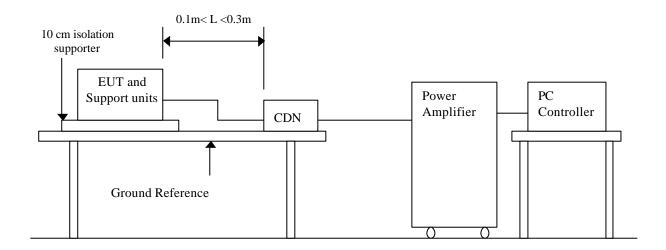
**Performance Criterion:** A (Standard Required)

**Teste d by** : Marion Yu

**Temperature** : 17°C **Humidity** : 51%

**Pressure**: 1009mbar

#### **Block Diagram of Test Setup:**



# **Test Procedure:**

- 1. The EUT and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- 2. Set the testing parameters of CS test software as per IEC/EN 61000-4-6.
- 3. Recorded the test result in following table.

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#### **Test conditions:**

Frequency Range : 0.15MHz-80MHz
Frequency Step : 1% of fundamental

Dwell Time : 3 sec

Range (MHz)	Field	Modulation	Result (Pass/Fail)
0.15-80	3V	Yes	Pass

# **Performance & Result:**

	Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.			
	Criterion B:	<b>B:</b> The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.			
	Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.			
Ol	oservation:	No function degraded during the tests.			

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# 15 POWER FREQUENCY MAGNETIC FIELD IMMUNITY TEST

Port : Enclosure

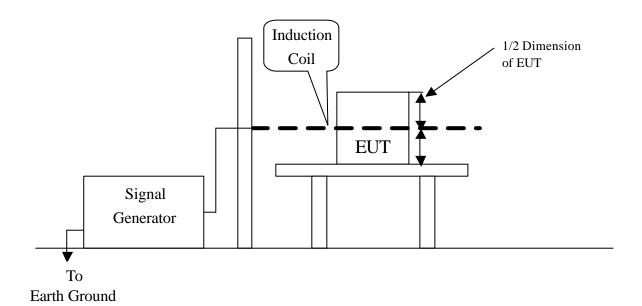
**Basic Standard**: IEC/EN 61000-4-8

**Requirements** : 1 A/m

**Performance Criterion:** A (Standard Required)

Tested by : N/A
Temperature : N/A
Humidity : N/A
Pressure : N/A

# **Block Diagram of Test Setup:**



# **Test Procedure:**

- 1. The EUT and support units were located on Ground Reference Plane with the interposition of a 0.1 m thickness insulation support.
- 2. Put the induction coil on horizontal direction. ( X direction )
- 3. Recorded the test result as shown in following table.
- 4. Rotated the induction coil by 90° (Y direction) then repeat step 3.
- 5. Rotated the induction coil by 90° ( Z direction ) then repeat step 3.

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**Test conditions:** 

Field Strength: 1A/m Power Freq.: 50Hz Orientation: X, Y, Z

Orientation	Field	Result (Pass/Fail)	Remark

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Performance &	& Result:
Criterion A:	The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.
Criterion B:	The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of performance is however allowed.
Criterion C:	Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.
	☐ PASS ☐ FAIL
Observation:	The EUT is not containing any component that is susceptible to a 50 Hz or 60 Hz magnetic field. Therefore, this requirement is not applicable to the EUT.

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# 16 VOLTAGE DIPS / SHORT INTERRUPTIONS

**Port** : AC mains

**Basic Standard**: IEC/EN 61000-4-11

**Requirement**: PHASE ANGLE 0, 45, 90, 135, 180, 225, 270, 315 degrees

Test Interval : Min. 10 sec.
Tested by : Marion Yu

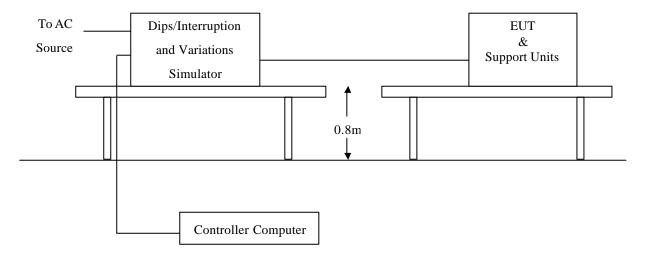
**Temperature** : 17°C **Humidity** : 51%

Pressure : 1009mbar

Voltage Dips	Test Level % U <sub>T</sub>	Reduction (%)	Duration ( periods )	Performance Criterion
	<5	>95	0.5	В
	70	30	25	С

Voltage Interceptions	Test Level % U <sub>T</sub>	Reduction (%)	Duration ( periods )	Performance Criterion
	<5	>95	250	С

# **Block Diagram of Test Setup:**



# **Test Procedure:**

- 1. The EUT and support units were located on a wooden table, 0.8 m away from ground floor.
- 2. Set the parameter of tests and then Performed the test software of test simulator.
- 3. Changed Condition to occur at 0 degree crossover point of the voltage waveform.
- 4. Recorded the test result in test record form.

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#### **Test conditions:**

The duration with a sequence of three dips/interruptions with interval of 10 sec. minimum (Between each test event )

## **Voltage Dips:**

Test Level % U <sub>T</sub>	Reduction (%)	Duration (periods)	Observation	Meet Performance Criterion	
0	100	0.5	Normal	A	
70	30	25	Normal	A	

## **Voltage Interruptions:**

Test Level % U <sub>T</sub>	Reduction (%)	Duration (periods)	Observation	Meet Performance Criterion
0	100	250	EUT shut down, but EUT can be auto recovered after it restart.	С

**Note:** "Normal" means no any functions degrade during and after the test.

## **Performance & Result:**

**Criterion A:** The apparatus continues to operate as intended. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance.

Criterion B: The apparatus continues to operate as intended after the test. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer, when the apparatus is used as intended. In some cases the performance level may be replaced by a permissible loss of performance. During the test, degradation of

performance is however allowed.

**Criterion C:** Temporary loss of function is allowed, provided the functions self recoverable or can be restored by the operation of controls.

	☐ FAIL					
Observation: No function degraded during the tests.						

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# APPENDIX I - PHOTOGRAPHS OF TEST SETUP LINE CONDUCTED EMISSION TEST (EN 55022)





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# COMMON MODE CONDUCTED EMISSION TEST

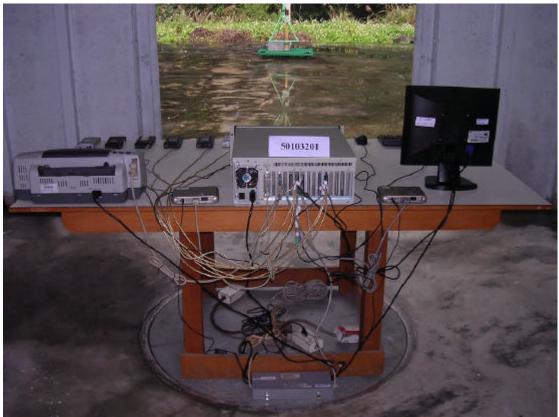




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# RADIATED EMISSION TEST





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# POWER HARMONIC & VOLTAGE FLUCTUATION / FLICKER TEST



## ELECTROSTATIC DISCHARGE TEST



Page 41 Rev. 00

## RADIATED ELECTROMAGNETIC FIELD TEST



## FAST TRANSIENTS/BURST TEST

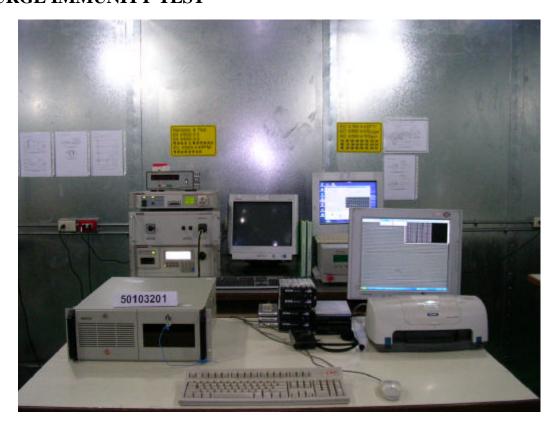


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# (IEC 61000-4-4 FOR I/O)



# **SURGE IMMUNITY TEST**



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# CONDUCTED DISTURBANCE, INDUCED BY RADIO-FREQUENCY FIELDS TEST



# (IEC 61000-4-6 FOR I/O)



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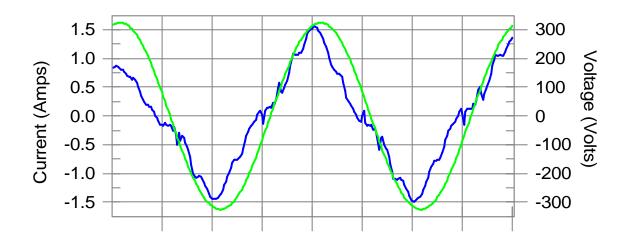
# **VOLTAGE DIPS / INTERRUPTION TEST**



## APPENDIX II – TEST RESULT OF EN 61000-3-3

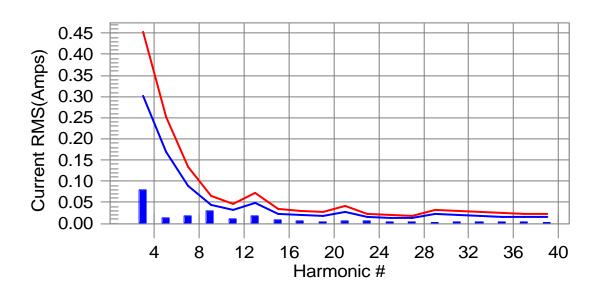
Test Result: Pass Source qualification: Normal

## Current & voltage waveforms



## **Harmonics and Class D limit line**

## **European Limits**



Test result: PassWorst harmonic was #9 with 43.20 % of the limit.

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Test Result: Pass Source qualification: Normal

Highest parameter values during test:

**V\_RMS (Volts): 230.07** 

 I\_Peak (Amps):
 1.563
 I\_RMS (Amps):
 0.794

 I\_Fund (Amps):
 0.812
 Crest Factor:
 3.002

 Power (Watts):
 172
 Power Factor:
 0.946

Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.000						
3	0.078	0.302	25.9	0.080	0.452	17.60	Pass
4	0.000						
5	0.014	0.169	8.1	0.014	0.253	5.56	Pass
6	0.000						
7	0.017	0.089	18.7	0.017	0.133	12.94	Pass
8	0.000						
9	0.028	0.044	64.0	0.029	0.067	43.20	Pass
10	0.000						
11	0.009	0.031	29.5	0.010	0.047	21.23	Pass
12	0.000						
13	0.008	0.049	31.6	0.018	0.073	24.19	Pass
14	0.000						_
15	0.009	0.023	40.3	0.010	0.034	28.14	Pass
16	0.000					10.00	_
17	0.006	0.020	27.2	0.006	0.030	19.28	Pass
18	0.000	0.040	40.0	0.004	0.007	44.05	
19	0.004	0.018	19.6	0.004	0.027	14.05	Pass
20 21	0.000 0.003	0.028	21.0	0.006	0.042	15 10	Boos
21	0.003	0.026	21.0	0.006	0.042	15.18	Pass
23	0.005	0.015	35.4	0.006	0.022	26.81	Pass
23 24	0.000	0.015	33.4	0.000	0.022	20.01	газэ
25	0.004	0.014	28.4	0.005	0.020	22.68	Pass
26	0.000	0.014	20.4	0.003	0.020	22.00	1 433
27	0.002	0.013	19.2	0.003	0.019	14.77	Pass
28	0.000	0.010	10.2	0.000	0.010	1-11.1	. 400
29	0.001	0.022	9.0	0.003	0.033	7.77	Pass
30	0.000						
31	0.002	0.020	14.7	0.004	0.030	14.62	Pass
32	0.000						
33	0.001	0.018	13.9	0.004	0.026	14.15	Pass
34	0.000						
35	0.001	0.017	13.2	0.004	0.025	15.40	Pass
36	0.000						
37	0.001	0.016	9.4	0.003	0.024	12.87	Pass
38	0.000						
39	0.001	0.015	6.4	0.002	0.022	8.68	Pass
40	0.000						

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Test Result: Pass Source qualification: Normal

## **Highest parameter values during test:**

Voltage (Vrms): 230.07

 I\_Peak (Amps):
 1.563
 I\_RMS (Amps):
 0.794

 I\_Fund (Amps):
 0.812
 Crest Factor:
 3.002

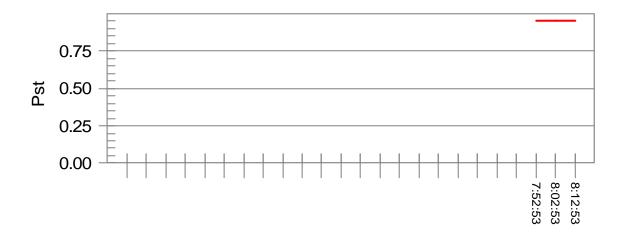
 Power (Watts):
 172
 Power Factor:
 0.946

Harm#	Harmonics V-rms	Limit V-rms	% of Limit	Status
2	0.112	0.460	24.29	ок
3	0.398	2.070	19.21	OK
4	0.042	0.460	9.08	OK
5	0.033	0.920	3.57	OK
6	0.052	0.460	11.25	OK
7	0.031	0.690	4.49	OK
8	0.035	0.460	7.70	OK
9	0.064	0.460	13.88	OK
10	0.021	0.460	4.48	OK
11	0.047	0.230	20.50	OK
12	0.020	0.230	8.83	OK
13	0.048	0.230	20.80	OK
14	0.020	0.230	8.86	OK
15	0.033	0.230	14.16	OK
16	0.014	0.230	6.19	OK
17	0.015	0.230	6.49	OK
18	0.023	0.230	10.03	OK
19	0.016	0.230	7.05	OK
20	0.020	0.230	8.58	OK
21	0.020	0.230	8.59	OK
22	0.019	0.230	8.10	OK
23	0.063	0.230	27.38	OK
24	0.022	0.230	9.58	OK
25	0.085	0.230	36.80	OK
26	0.027	0.230	11.55	OK
27	0.036	0.230	15.67	OK
28	0.023	0.230	10.15	OK
29	0.020	0.230	8.87	OK
30	0.050	0.230	21.93	OK
31	0.012	0.230	5.29	OK
32	0.021	0.230	9.24	OK
33	0.012	0.230	5.32	OK
34	800.0	0.230	3.62	OK
35	0.021	0.230	9.12	OK
36	0.007	0.230	3.25	OK
37	0.016	0.230	7.11	OK
38	0.005	0.230	2.25	OK
39	0.008	0.230	3.52	OK
40	0.010	0.230	4.42	OK

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Test Result: Pass Status: Test Completed

## Pst<sub>i</sub> and limit line European Limits



## Time is too short for Plt plot

## Parameter values recorded during the test:

Vrms at the end of test (Volt):	229.59			
Highest dt (%):	0.00	Test limit (%):	3.14	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.00	Test limit (%):	3.14	Pass
Highest dmax (%):	0.00	Test limit (%):	3.80	Pass
Highest Pst (10 min. period):	0.001	Test limit:	0.950	Pass
Highest Plt (2 hr. period):	0.001	Test limit:	0.617	Pass

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# APPENDIX III - TEST RESULT OF FINAL DATAS

**Conducted Emission Plot** 

**Radiated Emission Data** 

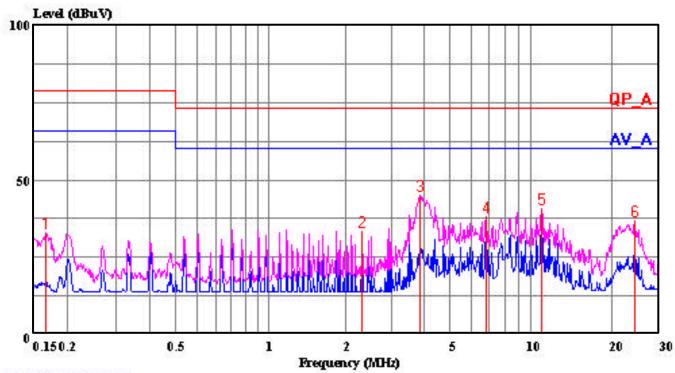
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No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 15 File#: 50103201CB.EMI Date: 2005-01-05 Time: 10:18:12



## (CCS Conduction B)

Trace: 14 13 Ref Trace:

Condition: LINE

Report No. : 50103201 Test Engr. : WEBBER JUNG

Company : AAEON Technology Inc.

EUT : HSB-835A

Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : Normal Mode

Page	:	-
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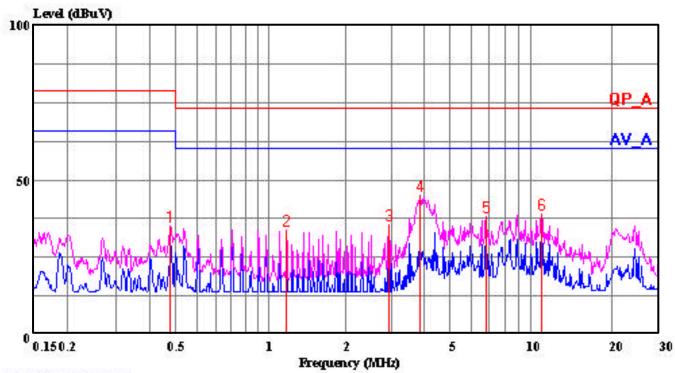
		Read			Limit	Over	
	Freq	Level	Factor	Level	Line	Limit	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	
1	0.166	23.06	9.97	33.03	79.00	-45.97	Peak
2	2.422	23.10	10.02	33.12	73.00	-39.88	Peak
3	3.964	35.06	10.08	45.14	73.00	-27.86	Peak
4	6.914	27.76	10.12	37.88	73.00	-35.12	Peak
5	11.080	30.36	10.19	40.55	73.00	-32.45	Peak
6	24.400	26.20	10.48	36.69	73.00	-36.31	Peak



No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 12 File#: 50103201CB.EMI Date: 2005-01-05 Time: 10:14:19



## (CCS Conduction B)

Trace: 11 10 Ref Trace:

Condition: NEUTRAL
Report No. : 50103201
Test Engr. : WEBBER JUNG

Company : AAEON Technology Inc.

EUT : HSB-835A

Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A

Mode of Op. : Normal Mode

Page:	1	1
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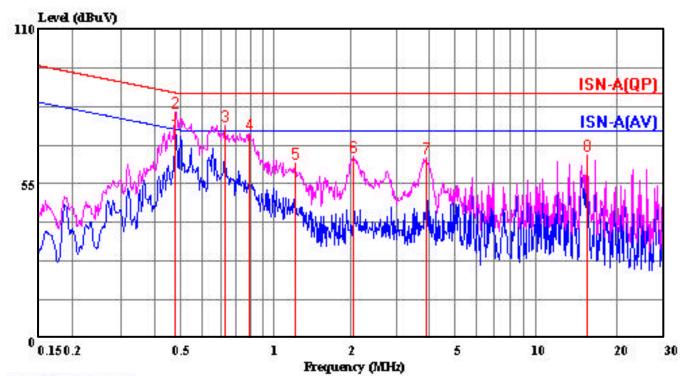
		Read			Limit	Over	
	Freq	Level	Factor	Level	Line	Limit	Remark
	MHz	dBuV	dВ	dBuV	dBuV	dВ	
1	0.479	25.02	9.98	35.00	79.00	-44.00	Peak
2	1.276	23.92	10.00	33.92	73.00	-39.08	Peak
3	3.025	25.30	10.04	35.34	73.00	-37.66	Peak
4	3.964	35.04	10.08	45.12	73.00	-27.88	Peak
5	6.914	27.76	10.12	37.88	73.00	-35.12	Peak
6	11.080	28.68	10.19	38.87	73.00	-34.13	Peak



No. 199, Chung Sheng Road, Hsin Tien City, Taipei, Taiwan, R.O.C.

Tel:02-2217-0894 Fax:02-2217-1029

Data#: 20 File#: 50103201CB.EMI Date: 2005-01-05 Time: 10:26:06



## (CCS Conduction B)

Trace: 17 16 Ref Trace:

Condition: COMMON
Report No. : 50103201
Test Engr. : WEBBER JUNG

Company : AAEON Technology Inc.

EUT : HSB-835A

Test Config : EUT / ALL PERIPHERALS Type of Test: EN 55022 CLASS A Mode of Op. : ISN 100 Mbps (Worst)

Page	•	1

	Freq	Read Level	Factor	Level	Limit Line	Over Limit	Remark
	MHz	dBuV	dB	dBuV	dBuV	dB	<del></del>
1 2 3 4 5	0.479 0.479 0.724 0.899 1.317 2.167	52.39 60.08 55.68 52.56 42.46 44.70	20.28 20.28 20.23 20.20 20.16 20.12	72.67 80.36 75.91 72.76 62.62 64.82	87.36 87.00 87.00 87.00		Peak Peak Peak
7	3.985 15.552	43.96 44.98	20.18	64.14 65.18		-22.86 -21.82	

Site I

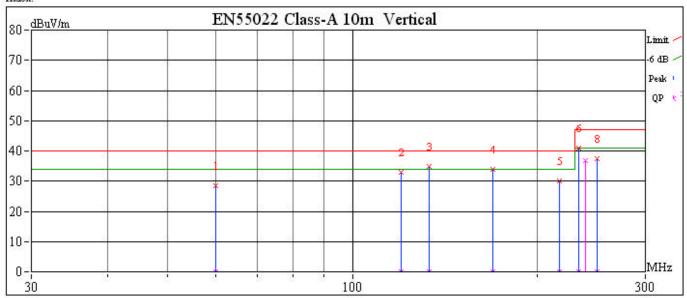


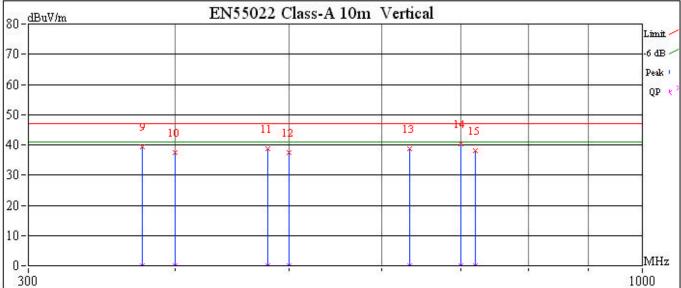
Custom Name: AAEON Technology Inc.

Model Name: HSB-835A Test Mode: Normal Mode Project No.: 50103201 Engineer Name: Webber Jung

Date: 2005-01-04

#### Index:





	Freq(MHz)	Peak(dBuV/m)	QP(dBuV/m)	Margin(dB)	Limit(dBuV/m)	Reading(dBuV)	Factor(dB)	Height	Degree	Comment
1	59.9300	28.58		-11.42	40.00	45.22	-16.64	100	0	
2	120.0400	32.89		-7.11	40.00	42.44	-9.55	100	0	
3	133.1100	34.94		-5.06	40.00	44.89	-9.95	100	0	
4	169.5700	33.88		-6.12	40.00	45.34	-11.46	100	0	
5	217.1600	29.96	K	-10.04	40.00	40.34	-10.38	100	0	
6	233.5100	41.02		-5.98	47.00	50.16	-9.14	100	0	
7	240.0490	-8.64	36.86	-10.14	47.00	45.50	-8.64	100	0	
8	250.0120	37.56	V2	-9.44	47.00	45.44	-7.88	100	0	
9	375.0470	39.41		-7.59	47.00	43.79	-4.38	100	0	
0	400.0470	37.34		-9.66	47.00	40.99	-3.65	100	0	
1	480.0400	38.63		-8.37	47.00	40.17	-1.54	100	0	
2	499.8950	37.29		-9.71	47.00	38.38	-1.09	100	0	
3	633.2600	38.85	A.	-8.15	47.00	38.41	0.44	100	0	
4	700.5020	40.29		-6.71	47.00	39.95	0.34	100	0	
5	720.0850	38.07	Sh.	-8.93	47.00	37.34	0.73	100	0	

Site I

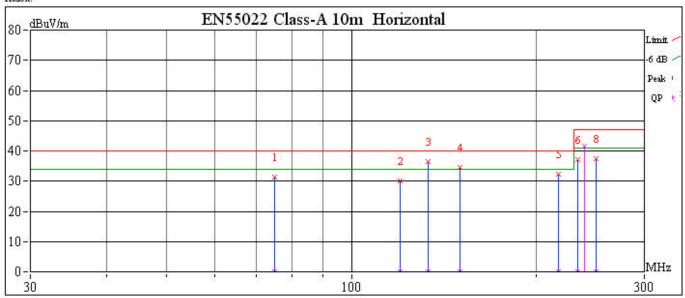


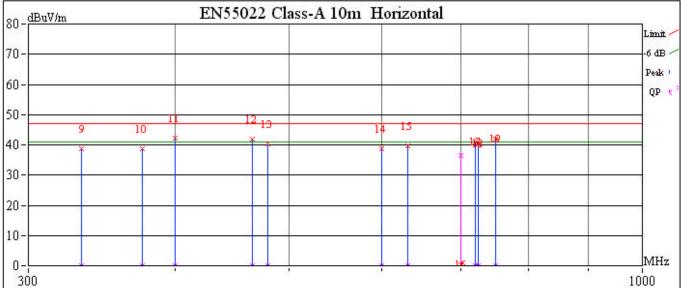
Custom Name: AAEON Technology Inc.

Model Name: HSB-835A Test Mode: Normal Mode gy Inc. Project No.: 50103201 Engineer Name: Webber Jung

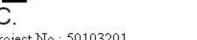
Date: 2005-01-04

#### Index:





	Freq(MHz)	Peak(dBuV/m)	QP(dBuV/m)	Margin(dB)	Limit(dBuV/m)	Reading(dBuV)	Factor(dB)	Height	Degree	Comment
1	74.9900	31.27		-8.73	40.00	46.70	-15.43	100	0	
2	120.0040	30.24	0	-9.76	40.00	39.79	-9.55	100	0	
3	133.2300	36.53		-3.47	40.00	46.48	-9.95	100	0	
4	150.0310	34.41		-5.59	40.00	45.02	-10.61	100	0	
5	217.2470	32.29	A c	-7.71	40.00	42.67	-10.38	100	0	
6	233.5300	37.27		-9.73	47.00	46.41	-9.14	100	0	
7	240.0550	-8.64	41.66	-5.34	47.00	50.30	-8.64	100	0	
8	250.0090	37.32	72	-9.68	47.00	45.20	-7.88	100	0	
9	332.6800	38.57		-8.43	47.00	44.27	-5.70	100	0	
10	375.0160	38.88	0	-8.12	47.00	43.26	-4.38	100	0	
11	400.0470	42.16		-4.84	47.00	45.81	-3.65	100	0	
12	465.7020	41.87		-5.13	47.00	43.73	-1.86	100	0	
3	480.0410	40.19	ē,	-6.81	47.00	41.73	-1.54	100	0	
4	600.0470	38.64		-8.36	47.00	38.10	0.54	100	0	
15	631.7400	39.65	76	-7.35	47.00	39.21	0.44	100	0	



Custom Name: AAEON Technology Inc.
Model Name: HSB-835A
Test Mode: Normal Model

COMPLIANCE

Project
Enginee

Test Mode: Normal Mode

Project No.: 50103201 Engineer Name: Webber Jung Date: 2005-01-04

C.	Frea(MHz)	Peak(dBuV/m)	OP(dBuV/m)	Margin(dB)	ass-A 10m Limit(dBuV/m)	Reading (dBuV)	Factor(dB)	Height	Degree	Comment
16				-10.67	47.00	0.02	0.33			- OSTALISTI
17	720.1950			-6.18			0.73			
18	725.1290	40.82	2	-6.67	47.00	2.	0.73		6 ~ "B	
1000				L STANCE		200000	V 100 100 100 100 100 100 100 100 100 10	1012000	335	
19	749.6950	41.78		-5.22	47.00	40.47	1.31	100	0	
	2					7.0	0		9 9	
						8			X 3	
			9				9		Se	
	8	E Y	8			30	8 3		6 8 8 8	
		7	ii .				20		764 (C)	
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	is a					38	38		A 6	
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						18	**		P 8	
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$\dashv$	ž :								0 0	
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Site I